Search Notes

Applicant(s)/Patent under Reexamination

10/810,574

Examiner

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Art Unit

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3618

SEARCHED				
Class	Subclass	Date	Examiner	
280	163 164.1 164.2	1/4/2007	HP	
	759			
	782			
	830			
239	284.1	1/4/2007	HP	
	106			
296	193.12	1/4/2007	HP	
15	250.02	1/4/2007	HP	
429	100	1/4/2007	НР	
220	562	1/4/2007	HP	
	890			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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